_	earch l	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/670,618	FLOCK ET AL.
Examiner	Art Unit
Michael J. Hayes	3763

	SEAR	CHED	
Class	Subclass	Date /	Examiner
604	20-2 57-6 82-84	2 8/28/ /	MJ/
	-		

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
	W 1		

(INCLUDING SEARCH STRATEGY)  DATE EXMR		
<del></del> .		